OptiMOS™-5 Power-Transistor

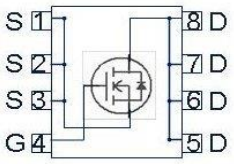
Product Summary

V_{DS}	100	V
$R_{DS(on),max}$	13	mΩ
I_D	40	A

Features

- OptiMOS™ - power MOSFET for automotive applications
- N-channel - Enhancement mode - Normal Level
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested
- Feasible for automatic optical inspection (AOI)

PG-TSDSON-8-33



Type	Package	Marking
IAUZ40N10S5N130	PG-TSDSON-8-33	5N1N130

Maximum ratings, at T_j=25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current[1)2)]	I_D	T_C=25°C, V_{GS}=10V	40	A
		T_C=100°C, V_{GS}=10V	35	
Pulsed drain current[2)]	$I_{D,pulse}$	T_C=25°C	160	
Avalanche energy, single pulse[2)]	E_{AS}	I_D=20A	60	mJ
Avalanche current, single pulse	I_{AS}	-	22	A
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P_{tot}	T_C=25°C T_J =175°C	68	W
Operating and storage temperature	T_j, T_{stg}	-	-55 ... +175	°C

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics[2]						
Thermal resistance, junction - case	R_{thJC}	-	-	-	2.2	K/W
Thermal resistance, junction - ambient	R_{thJA}	6 cm^2 cooling area[3]	-	-	62	
Electrical characteristics, at T_j=25 °C, unless otherwise specified						
Static characteristics						
Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS}=0V, I_D= 1mA	100	-	-	V
Gate threshold voltage	$V_{GS(th)}$	V_{DS}=V_{GS}, I_D=27µA	2.2	3.0	3.8	
Zero gate voltage drain current	I_{DSS}	V_{DS}=100V, V_{GS}=0V, T_j=25°C	-	-	1	µA
		V_{DS}=100V, V_{GS}=0V, T_j=125°C[2]	-	-	100	
Gate-source leakage current	I_{GSS}	V_{GS}=20V, V_{DS}=0V	-	-	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V_{GS}=6V, I_D=10A	-	14	17	mΩ
		V_{GS}=10V, I_D=20A	-	10.8	13	
Gate resistance[2]	R_G		-	1.2	-	Ω

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics[2]						
Input capacitance	C_{iss}	V_{GS}=0V, V_{DS}=50V, f=1MHz	-	1173	1525	pF
Output capacitance	C_{oss}		-	197	256	
Reverse transfer capacitance	C_{rss}		-	11	17	
Turn-on delay time	$t_{d(on)}$	V_{DD}=50V, V_{GS}=10V, I_D=40A, R_G=3.5Ω	-	4	-	ns
Rise time	t_r		-	1	-	
Turn-off delay time	$t_{d(off)}$		-	6	-	
Fall time	t_f		-	5	-	
Gate Charge Characteristics[2]						
Gate to source charge	Q_{gs}	V_{DD}=50V, I_D=20A, V_{GS}=0 to 10V	-	5.5	7.2	nC
Gate to drain charge	Q_{gd}		-	3.7	6.0	
Gate charge total	Q_g		-	17	24	
Gate plateau voltage	$V_{plateau}$		-	4.7	-	V
Reverse Diode						
Diode continous forward current[2]	I_S	T_C=25°C	-	-	40	A
Diode pulse current[2]	$I_{S,pulse}$		-	-	160	
Diode forward voltage	V_{SD}	V_{GS}=0V, I_F=20A, T_j=25°C	-	0.9	1.1	V
Reverse recovery time[2]	t_{rr}	V_R=40V, I_F=40A, di_F/dt=100A/µs	-	40	-	ns
Reverse recovery charge[2]	Q_{rr}		-	39	-	nC

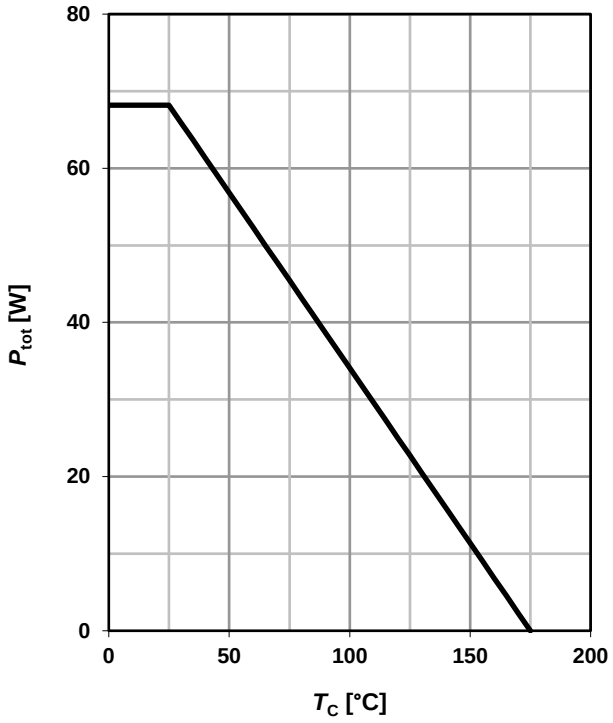
[1] Current is limited by package; with an R_{thJC} = 2.2K/W the chip is able to carry 50A at 25°C.

[2] The parameter is not subject to production test- verified by design/characterization.

[3] Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm^2 (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

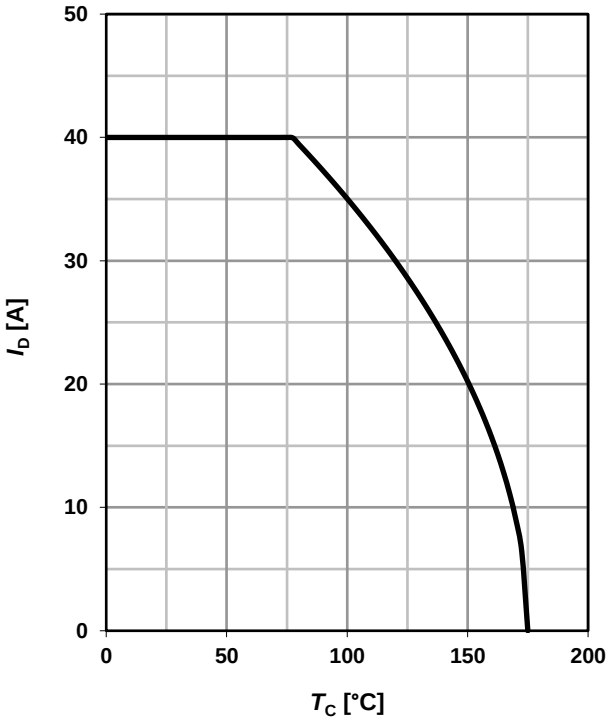
1 Power dissipation

$P_{tot} = f(T_C)$; $V_{GS} = 10$ V



2 Drain current

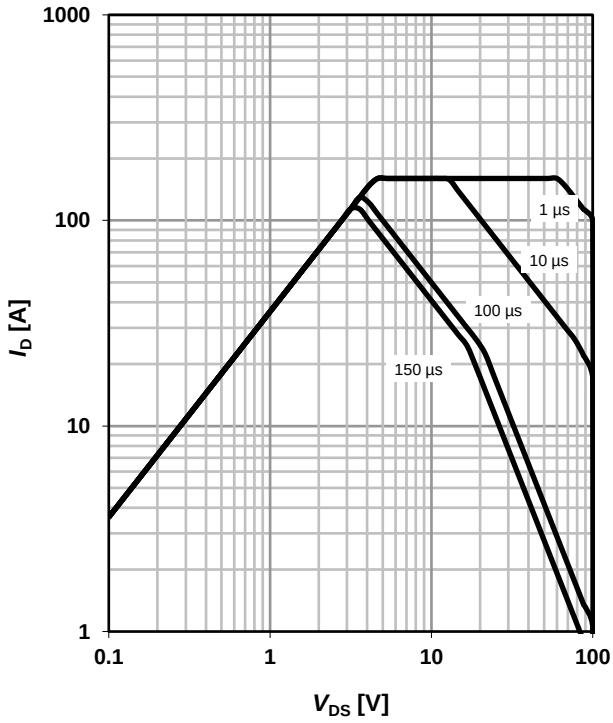
$I_D = f(T_C)$; $V_{GS} = 10$ V



3 Safe operating area

$I_D = f(V_{DS})$; $T_C = 25$ °C; $D = 0$

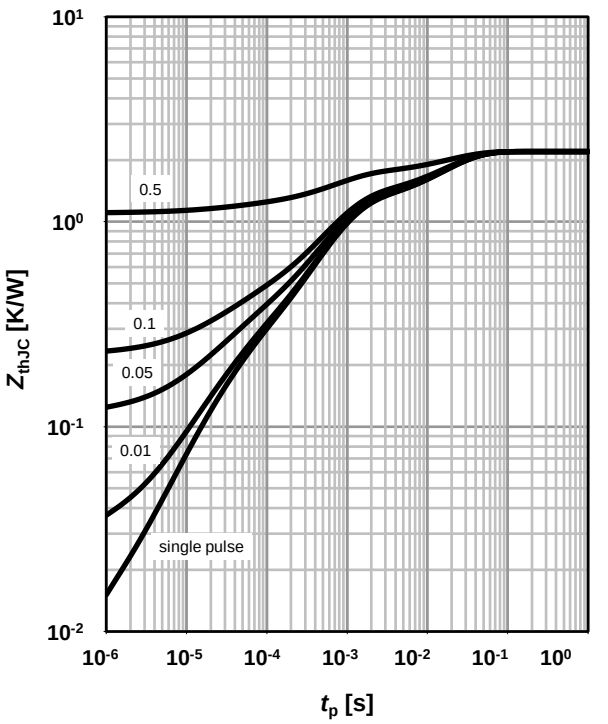
parameter: t_p



4 Max. transient thermal impedance

$Z_{thJC} = f(t_p)$

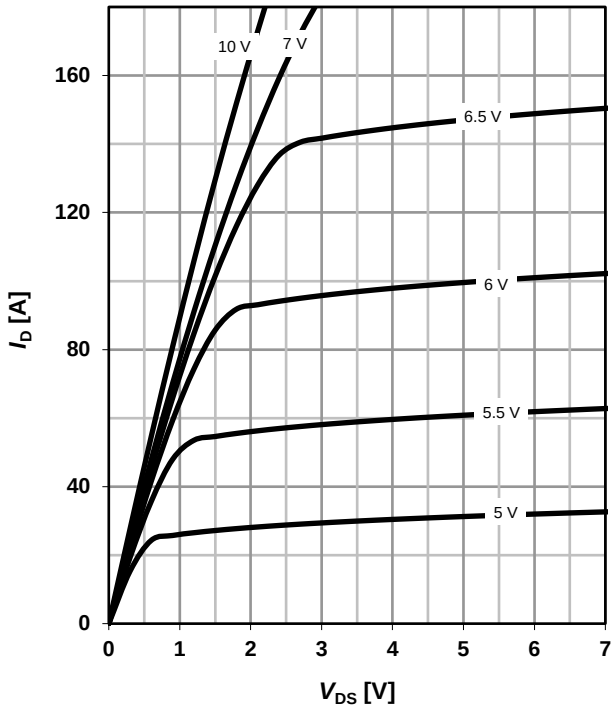
parameter: $D = t_p/T$



5 Typ. output characteristics

$I_D = f(V_{DS})$; $T_j = 25$ °C

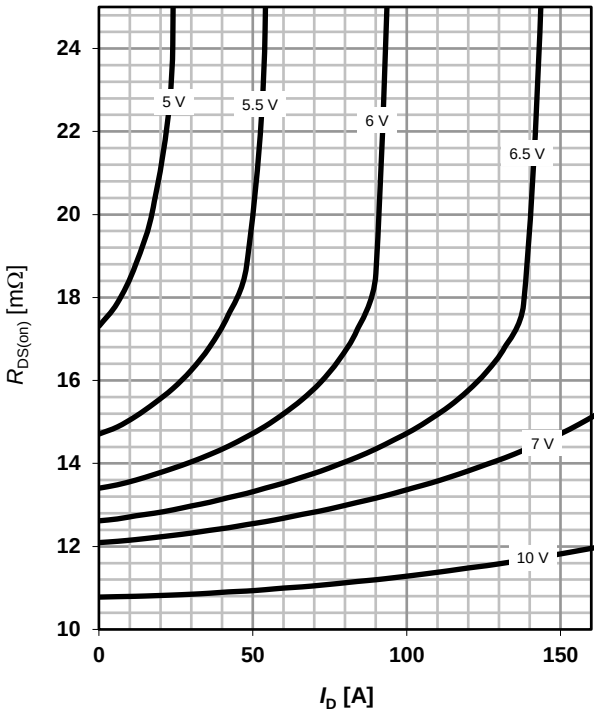
parameter: V_{GS}



6 Typ. drain-source on-state resistance

$R_{DS(on)} = f(I_D)$; $T_j = 25$ °C

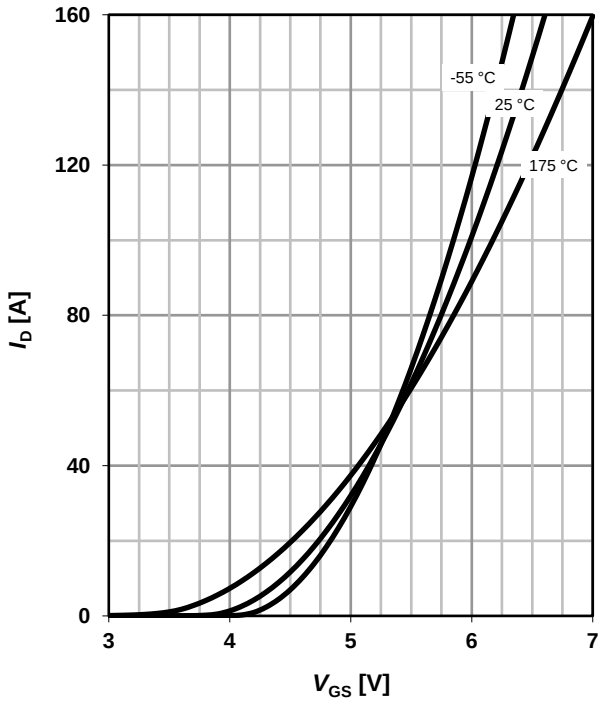
parameter: V_{GS}



7 Typ. transfer characteristics

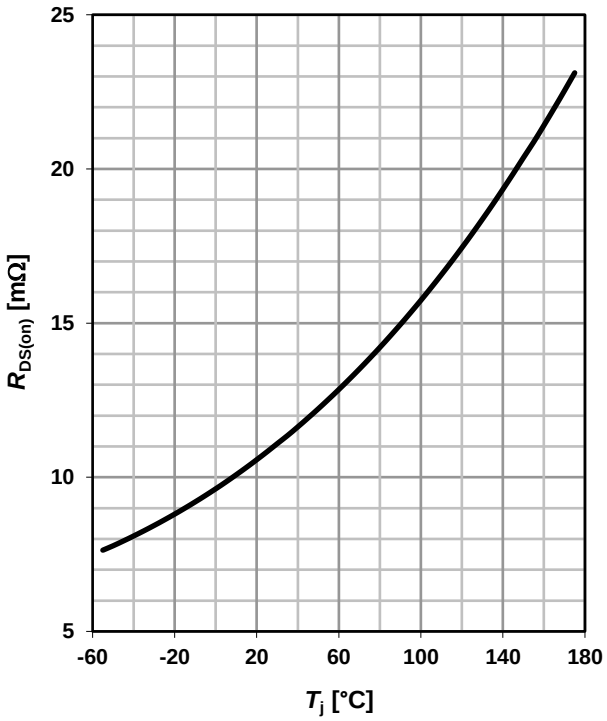
$I_D = f(V_{GS})$; $V_{DS} = 6$V

parameter: T_j



8 Typ. drain-source on-state resistance

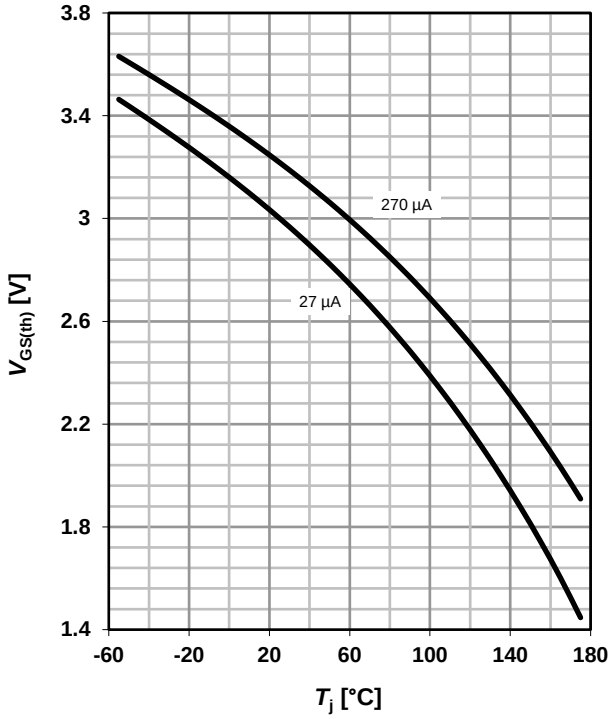
$R_{DS(on)} = f(T_j)$; $I_D = 20$ A; $V_{GS} = 10$ V



9 Typ. gate threshold voltage

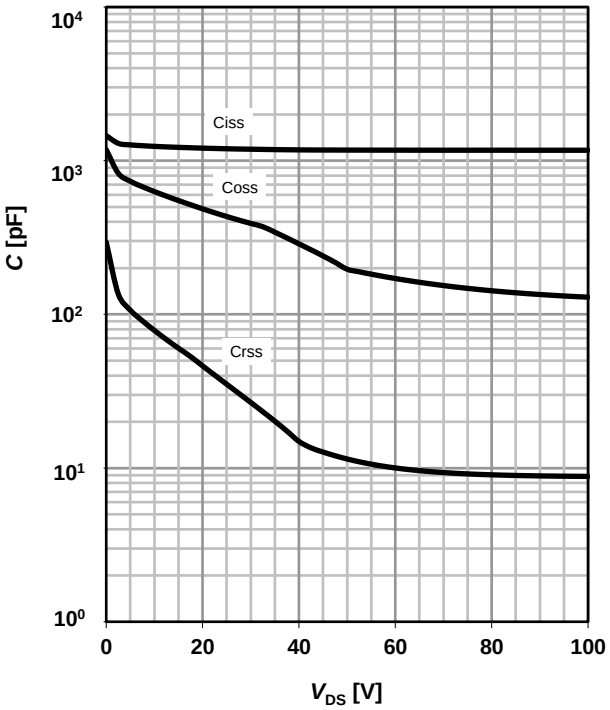
$V_{GS(th)} = f(T_j)$; $V_{GS} = V_{DS}$

parameter: I_D



10 Typ. capacitances

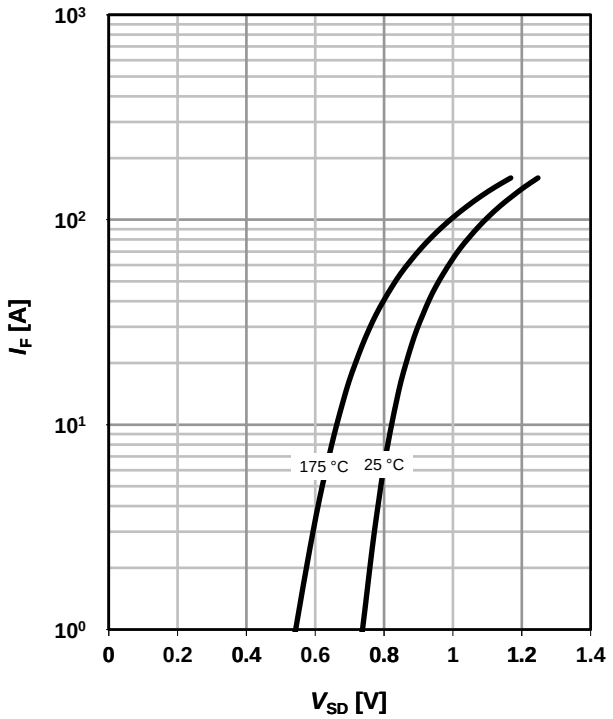
$C = f(V_{DS})$; $V_{GS} = 0$ V; $f = 1$ MHz



11 Typical forward diode characteristics

IF = f(V_{SD})

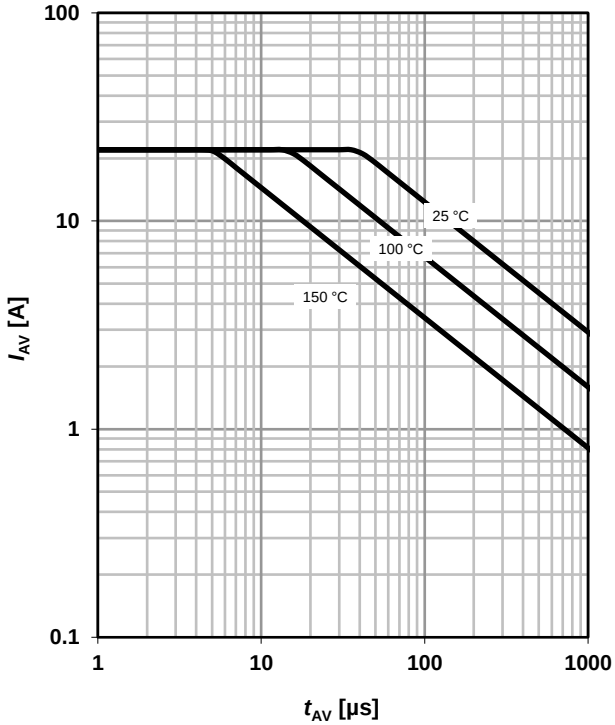
parameter: T_j



12 Avalanche characteristics

$I_{AS} = f(t_{AV})$

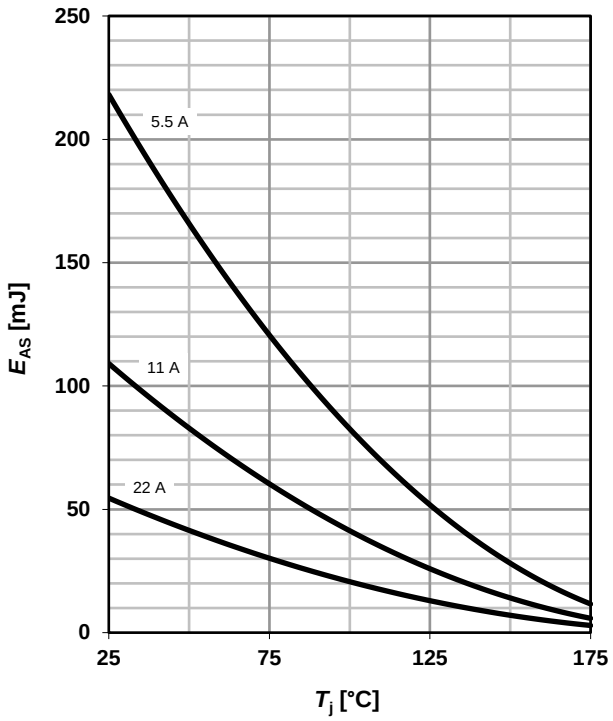
parameter: $T_{j(start)}$



13 Avalanche energy

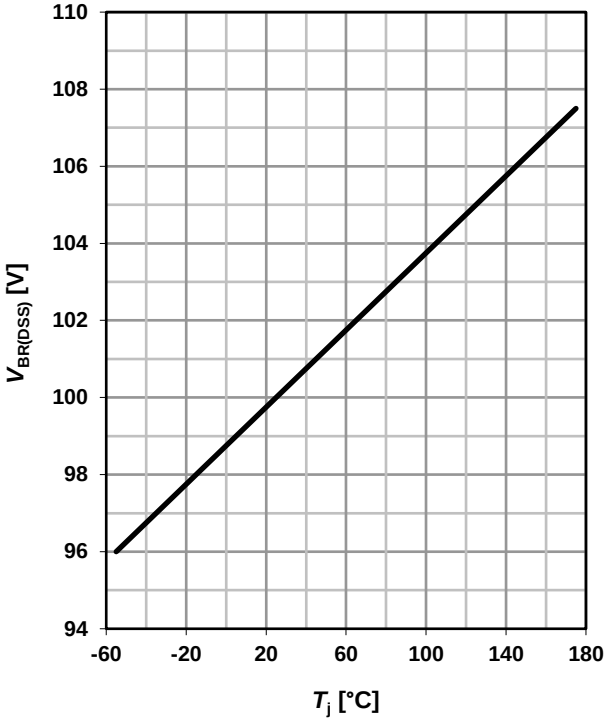
$E_{AS} = f(T_j)$

parameter: I_D



14 Drain-source breakdown voltage

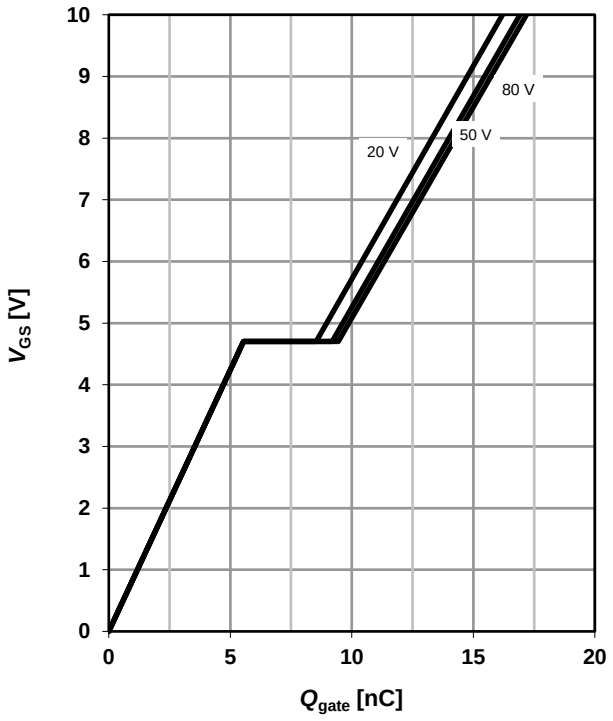
$V_{BR(DSS)} = f(T_j)$; $I_D = 1$ mA



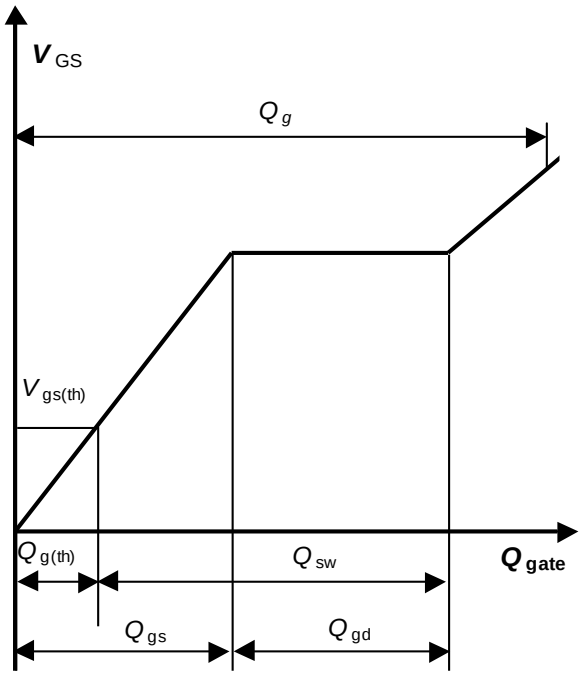
15 Typ. gate charge

$V_{GS} = f(Q_{gate})$; $I_D = 20$ A pulsed

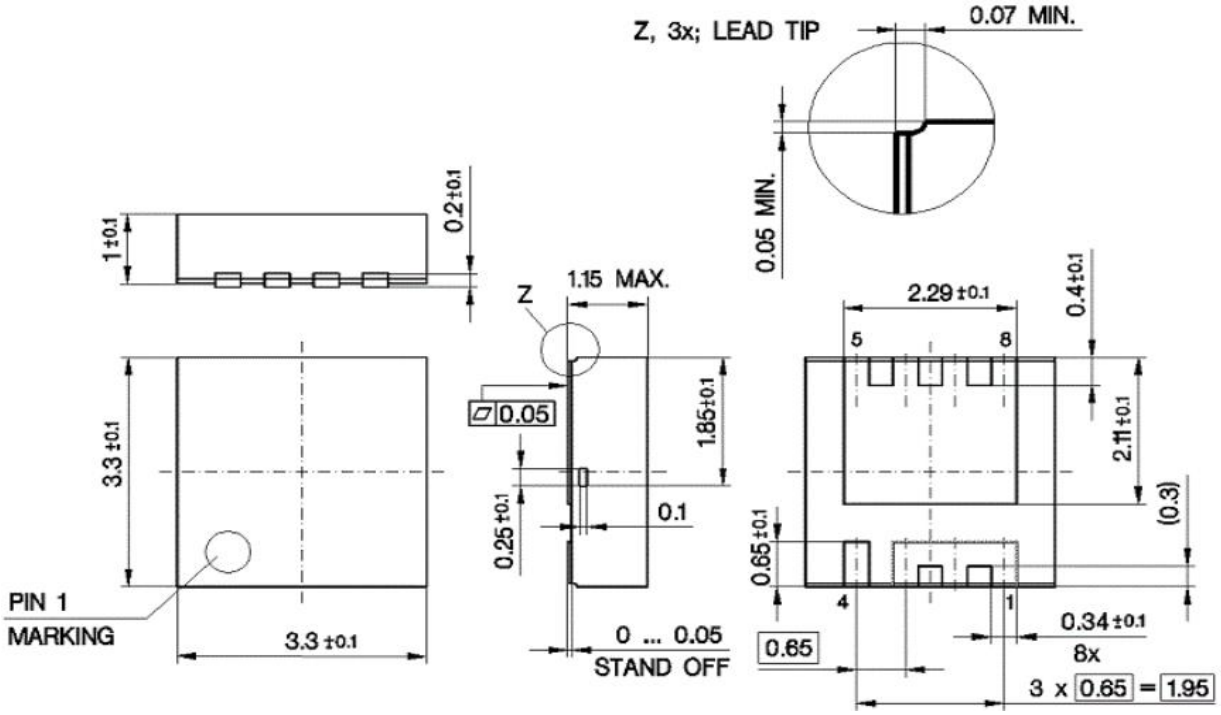
parameter: V_{DD}



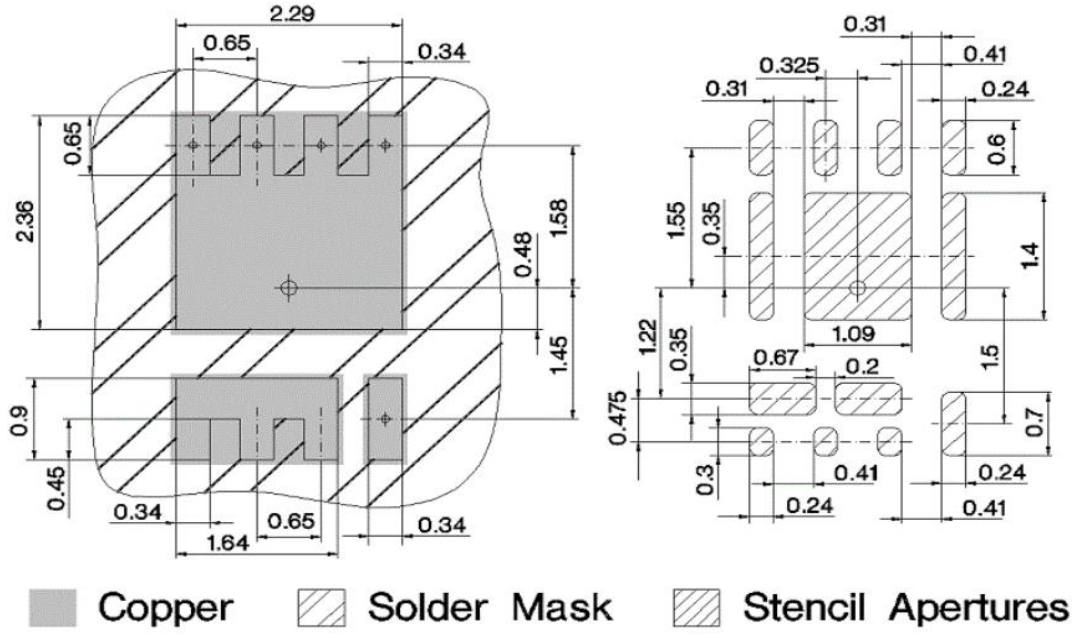
16 Gate charge waveforms



PG-TSDSON-8: Outline

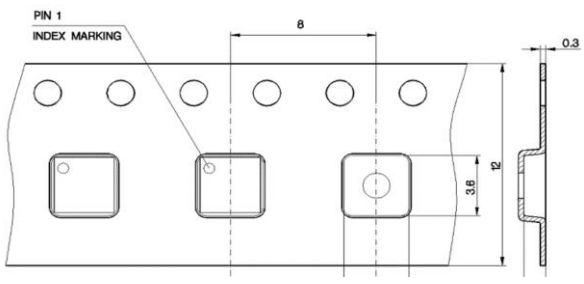


Footprint



Dimensions in mm

Packaging



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Revision History

Version	Date	Changes
Revision 1.0	23.07.2019	Final Data Sheet